

Day : Friday  
Date: 5/14/2004

**PALM INTRANET**

Time: 11:53:44

# **Inventor Name Search Result**

*for 10/084, 088*

Your Search was:

Last Name = CHOW

First Name = LEE

Application#	Patent#	Status	Date Filed	Title	Inventor Name 12
<u>60511787</u>	Not Issued	020	10/16/2003	METHOD TO ATTACH CARBON NANOTUBE PROBE TO SCANNING PROBE MICROSCOPY TIPS	CHOW, LEE
<u>60284360</u>	Not Issued	159	04/17/2001	ELECTROCHEMICAL DEPOSITION OF CARBON NANOTUBES FROM ORGANIC SOLUTION	CHOW, LEE
<u>60272155</u>	Not Issued	159	02/28/2001	FABRICATION OF NANOMETER SIZE THERMOCOUPLES AND HEATERS	CHOW, LEE
<u>60208203</u>	Not Issued	159	05/31/2000	"METAL/CDTE/CD1-XZNXS/TCO/GLASS": A NEW CDTE THIN FILM SOLAR CELL STRUCTURE	CHOW, LEE
<u>10764242</u> <i>Consider 1-6 only prod. remain</i>	Not Issued	019	01/01/0001	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	CHOW, LEE
<u>10424336</u>	Not Issued	030	04/25/2003	CARBON NANOTUBE WITH A GRAPHITIC OUTER LAYER: PROCESS AND APPLICATION	CHOW, LEE
<u>10119414</u>	Not Issued	094	04/09/2002	ELECTROCHEMICAL DEPOSITION OF CARBON NANOPARTICLES FROM ORGANIC SOLUTIONS	CHOW, LEE
<u>10084688</u>	Not Issued	071	02/27/2002	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	CHOW, LEE
<u>09528259</u>	<u>6582673</u>	150	03/17/2000	CARBON NANOTUBE WITH A GRAPHITIC OUTER LAYER: PROCESS AND APPLICATION	CHOW, LEE
<u>08272696</u>	Not	161 <i>and</i>	07/08/1994	MICROWAVE METHOD FOR	CHOW, LEE

*provisional*

*Discontinued*

*NO*

*NO*

*Yes close*

*NO*

*NO*

NO

	Issued			PRODUCING FULLERENES	
08176543	5510098 HAVE	150	01/03/1994	CVD METHOD OF PRODUCING AND DOPING FULLERENES	CHOW , LEE
07750309	5240749	150	08/27/1991	METHOD FOR GROWING A DIAMOND THIN FILM ON A SUBSTRATE BY PLASMA ENHANCED CHEMICAL VAPOR DEPOSITION	CHOW , LEE

NO

Inventor Search Completed: No Records to Display.

Search Another: Inventor

Last Name	First Name	
chow	lee	Search

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## Inventor Name Search Result

Your Search was:

Last Name = ZHOU

First Name = DAN

Application#	Patent#	Status	Date Filed	Title	Inventor Name 13
<u>60440406</u>	Not Issued	020	01/15/2003	TREATMENT FOR CANCERS	ZHOU, DAN
<u>60284360</u>	Not Issued	159	04/17/2001	ELECTROCHEMICAL DEPOSITION OF CARBON NANOTUBES FROM ORGANIC SOLUTION	ZHOU, DAN
<u>60272155</u>	Not Issued	159	02/28/2001	FABRICATION OF NANOMETER SIZE THERMOCOUPLES AND HEATERS	ZHOU, DAN
<u>60139623</u>	Not Issued	159	06/17/1999	INHIBITORS OF IL-12 PRODUCTION	ZHOU, DAN
<u>10764242</u>	Not Issued	019	01/01/0001	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	ZHOU, DAN
<u>10758589</u>	Not Issued	019	01/15/2004	TREATMENT FOR CANCERS	ZHOU, DAN
<u>10424336</u>	Not Issued	030	04/25/2003	CARBON NANOTUBE WITH A GRAPHITIC OUTER LAYER: PROCESS AND APPLICATION	ZHOU, DAN
<u>10335231</u>	Not Issued	094	12/30/2002	METHOD OF SWITCHING SYNCHRONIZATION OF PARALLEL-CONNECTED CONVERTER SYSTEM	ZHOU, DANGSHENG
<u>10119414</u>	Not Issued	094	04/09/2002	ELECTROCHEMICAL DEPOSITION OF CARBON NANOPARTICLES FROM ORGANIC SOLUTIONS	ZHOU, DAN
<u>10084688</u>	Not Issued	071	02/27/2002	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	ZHOU, DAN
<u>09594362</u>	<u>6384032</u>	150	06/15/2000	INHIBITORS OF IL-12	ZHOU, DAN

NO  
NO

				PRODUCTION	
<u>09528259</u>	<u>6582673</u>	150	03/17/2000	CARBON NANOTUBE WITH A GRAPHITIC OUTER LAYER: PROCESS AND APPLICATION	ZHOU, DAN
<u>09255919</u>	<u>6592839</u>	150	02/23/1999	TAILORING NANOCRYSTALLINE DIAMOND FILM PROPERTIES	ZHOU , DAN

Inventor Search Completed: No Records to Display.

	<b>Last Name</b>	<b>First Name</b>	
<b>Search Another: Inventor</b>	<input type="text" value="zhou"/>	<input type="text" value="Dan"/>	<input type="button" value="Search"/>

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## Inventor Name Search Result

Your Search was:

Last Name = STEVIE

First Name = FRED

Application#	Patent#	Status	Date Filed	Title	Inventor Name 34
<u>60272155</u>	Not Issued	159	02/28/2001	FABRICATION OF NANOMETER SIZE THERMOCOUPLES AND HEATERS	STEVIE, FRED
<u>60144105</u>	Not Issued	159	07/16/1999	PROBE FOR STYLUS NANOPROFILOMETRY AND METHOD OF MANUFACTURE THEREOF	STEVIE, FREDERICK A.
<u>60106694</u>	Not Issued	159	11/02/1998	NOVEL METHOD TO ENGINEER NITROGEN PROFILE IN SILICON DIOXIDE TO IMPROVE ITS RELIABILITY AND BLOCK BORON PENETRATION	STEVIE, FRED ANTHONY
<u>10764242</u>	Not Issued	019	01/01/0001	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	STEVIE, FRED
<u>10156242</u>	<u>6708574</u>	150	05/24/2002	ABNORMAL PHOTORESIST LINE/SPACE PROFILE DETECTION THROUGH SIGNAL PROCESSING OF METROLOGY WAVEFORM	STEVIE, FRED ANTHONY
<u>10122645</u>	Not Issued	095	04/12/2002	CALIBRATION STANDARD FOR HIGH RESOLUTION ELECTRON MICROSCOPY	STEVIE, FRED ANTHONY
<u>10084688</u>	Not Issued	071	02/27/2002	FABRICATION OF NANO-SCALE TEMPERATURE SENSORS AND HEATERS	STEVIE, FRED
<u>09836525</u>	Not Issued	061	04/17/2001	LABORATORY SPECIMEN SAMPLER WITH INTEGRATED SPECIMEN MOUNT	STEVIE, FRED A.
<u>09801455</u>	<u>6577970</u>	150	03/08/2001	METHOD OF DETERMINING A CRYSTALLOGRAPHIC QUALITY OF A MATERIAL	STEVIE, FRED A.

				LOCATED ON A SUBSTRATE	
<u>09727380</u>	Not Issued	164 <i>abd</i>	11/30/2000	METHOD OF DETERMINING THE SHAPE OF A PROBE FOR A STYLUS PROFILOMETER	STEVIE, FRED ANTHONY
<u>09727014</u>	6633032	150	11/30/2000	MASS SPECTROMETER PARTICLE COUNTER	STEVIE, FRED ANTHONY
<u>09653364</u>	6569690	150	08/31/2000 ?	MONITORING SYSTEM FOR DETERMINING PROGRESS IN A FABRICATION ACTIVITY	STEVIE, FRED ANTHONY
<u>09631545</u>	6627885	150	08/03/2000	METHOD OF FOCUSED ION BEAM PATTERN TRANSFER USING A SMART DYNAMIC TEMPLATE	STEVIE, FRED A.
<u>09631544</u>	Not Issued	161 <i>abd</i>	08/03/2000	FOCUSED PARTICLE BEAM SYSTEM USING A RETICLE HAVING AN OPENING FORMED THERETHROUGH AND A METHOD OF USE THEROF	STEVIE, FREDERICK A.
<u>09572107</u>	Not Issued	161 <i>abd</i>	05/17/2000	SYSTEM AND METHOD FOR SELECTING AN APPROPRIATE PROBE TIP FOR A SCANNING PROBE MICROSCOPE	STEVIE, FRED A.
<u>09567675</u>	6603119	150	05/09/2000	CALIBRATION METHOD FOR QUANTITATIVE ELEMENTAL ANALYSIS	STEVIE, FREDERICK A.
<u>09567373</u>	6519542	150	05/09/2000	METHOD OF TESTING AN UNKNOWN SAMPLE WITH AN ANALYTICAL TOOL	STEVIE, FREDRICK A.
<u>09567359</u>	6519543	150	05/09/2000	CALIBRATION METHOD FOR QUANTITATIVE ELEMENTAL ANALYSIS	STEVIE, FREDERICK A.
<u>09552892</u>	6425189	150	04/20/2000	PROBE TIP LOCATOR HAVING IMPROVED MARKER ARRANGEMENT FOR REDUCED BIT ENCODING ERROR	STEVIE, FREDERICK A.
<u>09535130</u>	Not Issued	160 <i>abd</i>	03/24/2000	SEMICONDUCTOR WAFER HAVING ANALYTICAL TEST PATTERN SITE	STEVIE, FREDERICK
<u>09527055</u>	Not Issued	161 <i>abd</i>	03/16/2000	DETECTION OF COPPER IN SILICON DIOXIDE	STEVIE, FRED ANTHONY
<u>09412130</u>	6405584	150	10/05/1999	PROBE FOR SCANNING PROBE MICROSCOPY AND RELATED METHODS	STEVIE , FRED ANTHONY

09386711	6250143	150	08/31/1999	A METHOD OF MAPPING A SURFACE USING A PROBE FOR STYLUS NANOPROFILOMETRY HAVING A NON-CIRCULAR CROSS-SECTION	STEVIE , FREDERICK A.
09337966	6362475	150	06/22/1999	SCANNING ELECTRON MICROSCOPE/ENERGY DISPERSIVE SPECTROSCOPY SAMPLE PREPARATION METHOD AND SAMPLE PRODUCED THEREBY	STEVIE , FREDERICK A.
09328560	6297503	150	06/09/1999	METHOD OF DETECTING SEMICONDUCTOR DEFECTS	STEVIE , FREDERICK A.
09320369	Not Issued	161 <i>del</i>	05/25/1999	SAMPLE HOLDER FOR MULTIPLE DIAGNOSTIC TOOLS AND METHODS OF MANUFACTURE AND OPERATION THEREOF	STEVIE , FRED A.
09315694	Not Issued	161 <i>del</i>	05/20/1999	METHOD FOR MAKING NITRIDED OXIDE LAYER AND DEVICES INCLUDING SAME	STEVIE , FREDERICK A.
09138741	6121624	150	08/24/1998	METHOD FOR CONTROLLED IMPLANTATION OF ELEMENTS INTO THE SURFACE OR NEAR SURFACE OF A SUBSTRATE	STEVIE , FREDERICK A.
09138740	6229141	150	08/24/1998	ANALYSIS OF ALKALI ELEMENTS IN INSULATORS USING SECONDARY ION MASS SPECTROMETRY	STEVIE , FREDERICK A.
09137053	Not Issued	169 <i>del</i>	08/20/1998	ANALYSIS OF ALKALI ELEMENTS IN INSULATORS USING SECONDARY ION MASS SPECTROMETRY	STEVIE , FREDERICK A.
08931066	5804460	150	09/15/1997	LINEWIDTH METROLOGY OF INTEGRATED CIRCUIT STRUCTURES	STEVIE , FRED A.
08366357	Not Issued	166 <i>del</i>	12/29/1994	LINEWIDTH METROLOGY OF INTEGRATED CIRCUIT STRUCTURES	STEVIE , FRED A.
07190721	4861126	150	05/05/1988	LOW TEMPERATURE INTRINSIC GETTERING TECHNIQUE	STEVIE , FRED A.
07115286	Not Issued	161 <i>del</i>	11/02/1987	LOW TEMPERATURE INTRINSIC GETTERING	STEVIE , FRED A.

				TECHNIQUE	
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	<input type="text" value="stevie"/>	<input type="text" value="fred"/>	

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	L #	Hits	Search Text	DBs	Time Stamp
1	L1	8	((("6569690") or ("6627885") or ("6121624") or ("5804460"))).PN.  <i>for inventor Name Search</i>	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:02
2	L2	12144	((427/526,531,562,564 ,595,96,77,123,125) or (438/584,652,622,650, 666,674,685,686,688)) .CCLS.	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:06
3	L3	6728	FIB focused adj ion adj beam	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:07
4	L4	47300	ion near (beam ray stream)	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:09

*EAST Search - update +  
10/084688*

	L #	Hits	Search Text	DBs	Time Stamp
5	L5	658	2 and 4	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:09
6	L6	75	2 and 3	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:10
7	L7	586	5 not 6	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:10
8	L8	19803 1	temperature near sensor or ("bi-metal" bimetal)adj junction or thermocouple	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:12

	L #	Hits	Search Text	DBs	Time Stamp
9	L9	3	8 and 6	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:13
10	L10	31	8 and 7	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:13
11	L11	72	6 not 9	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:14
12	L12	555	7 not 10	USPA T; US-P GPUB ; EPO; JPO; DERW ENT; IBM_ TDB	2004/05/1 4 13:14